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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

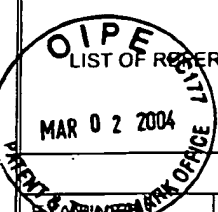
SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 220471US2S		SERIAL NO. 10/091,423	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yusuke KAWAGUCHI, et al.			
				FILING DATE March 7, 2002		GROUP 2826	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Re</i>	AA	4,941,026	07/10/90	TEMPLE			
<i>Re</i>	AB	5,637,898	06/10/97	BALIGA			
<i>Re</i>	AC	5,679,966	10/21/97	BALIGA ET AL.			
<i>Re</i>	AD	5,844,273	12/01/98	KONISHI			
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>Re</i>	AO	EP 0 238 749 A2	09/30/87	EUROPEAN			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	BALIGA, B. J., "Critical Nature of Oxide/Interface Quality for SiC Power Devices", 9 th Biennial Conference on Insulating Films on Semiconductors, Villard De Lans, France, 7-10 June 1995, Microelectronic Engineering, June 1995, Elsevier Publishers B.V., Amsterdam, Netherlands, vol. 28, no. 1-4, pages 177-184.					
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>SM</i> <i>PAUL BRIDEN</i>					Date Considered <i>02/08/05</i>		
*Examiner: Initial reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Linked to OPTMS	
DATE	CASE ID

COPY

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<div style="text-align: center;">  </div>				APPLICANT Yusuke KAWAGUCHI, et al.			
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Examiner [Signature] PAU TRASH				Date Considered 02/08/05			
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